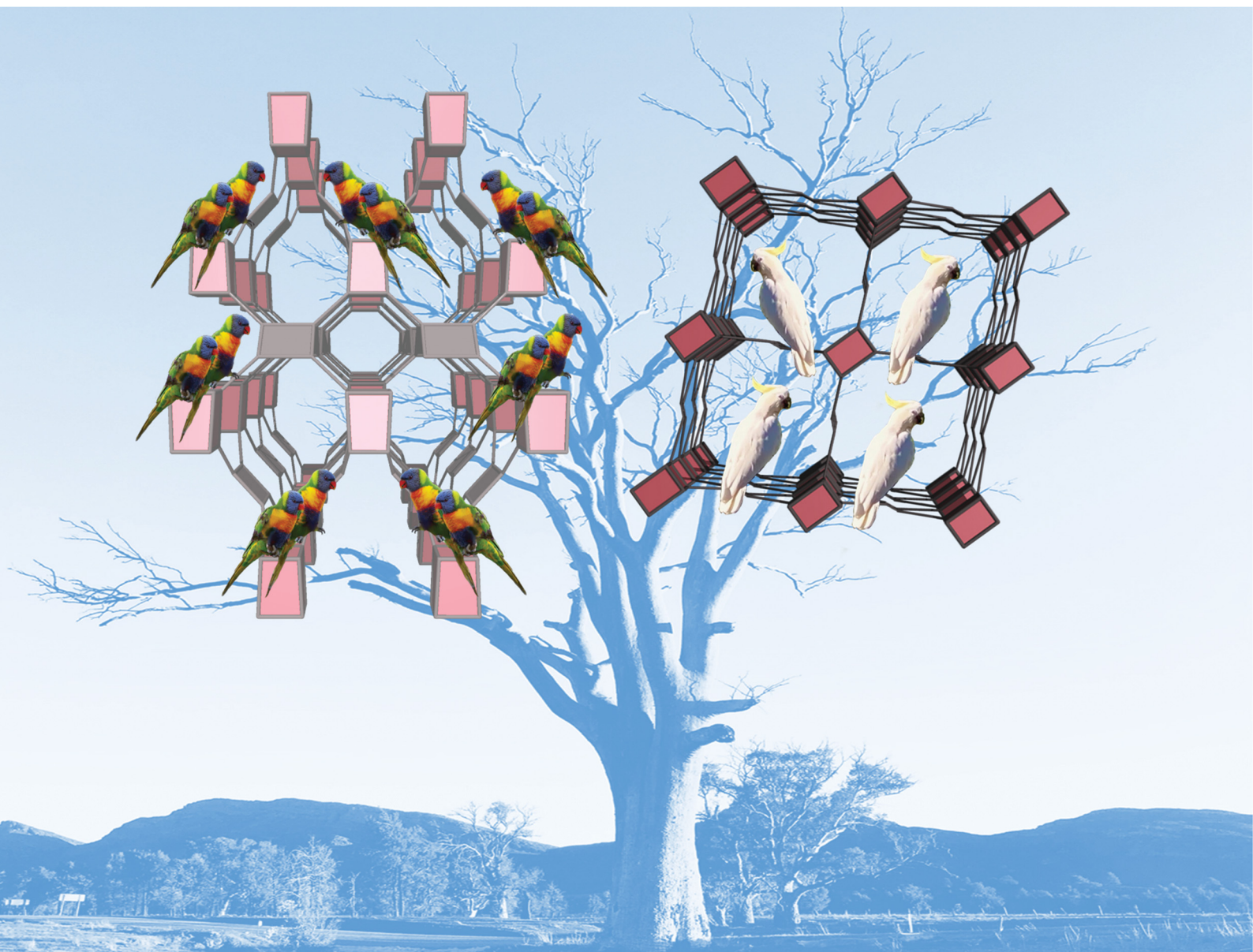


Journal of Materials Chemistry C

Materials for optical, magnetic and electronic devices

rsc.li/materials-c



ISSN 2050-7526

PAPER

Jack D. Evans, Christian J. Doonan, Christopher J. Sumby *et al.*
Topological analysis and control of post-synthetic metalation
sites in Zr-based metal-organic frameworks